

Form PTO-1449
(Rev. 8-83)U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-1961

Serial No. 09/295,607

INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 22, 1999

Group Art Unit: 2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
Loke	5,254,208	10/19/1993	Zhang			
Loke	5,716,857	02/10/1998	Zhang			
Loke	6,008,078	12/28/1999	Zhang			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
Loke	02-140915	05/30/1990	JP			Full Eng	
	02-210832	08/22/1990	JP			Eng Abst	
	04-080914	03/13/1992	JP			Eng Abst	
	04-093080	03/25/1992	JP			Eng Abst	
	05-121733	05/18/1993	JP			Eng Abst	
	57-170571	10/20/1982	JP			Eng Abst	
	62-052968	03/07/1987	JP			Eng Abst	
	62-298151	12/25/1987	JP			Full Eng	
Loke	63-142807	06/15/1988	JP			Full Eng	

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Loke	2001/0050664	12/13/2001	Yamazaki et al.			
	4,468,855	09/04/1984	Sasaki			
	4,651,182	03/17/1987	Yamazaki			
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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
Loke	0 072 216	02/16/1983	EP			Full Eng
	0 486 284	05/20/1992	EP			Full Eng
	02-153896	06/13/1990	JP			Eng Abst
	03-022540	01/30/1991	JP			Full Eng
	04-085922	03/18/1992	JP			Eng Abst
	04-133029	05/07/1992	JP			Eng Abst
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	04-190329	07/08/1992	JP			Eng Abst
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Loke	58-071663	04/28/1983	JP			Eng Abst

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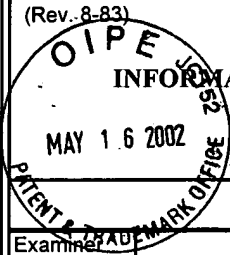
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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No	
<i>Loke</i> ↓ <i>Loke</i>	58-118154	07/14/1983	JP			Full Eng	
	60-186066	09/21/1985	JP			Eng Abst	
	60-245173	12/04/1985	JP			Full Eng	
	62-007691	01/14/1987	JP			Eng Abst	
	62-054422	03/10/1987	JP			Eng Abst	
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	63-056912	03/11/1988	JP			Eng Abst	
OTHER DOCUMENT (Including Author, Title, Date, Pertinent Pages, Etc.)							
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<i>Loke</i>	Hanada et al., "Preparation and Physical Properties of rf-Sputtered Amorphous Films in the Al O -AlN System", pp. 227-235, 1991, Journal of Non-Crystalline Solids, Vol. 135						
<p style="font-size: 2em; font-weight: bold; transform: rotate(-5deg);">BEST AVAILABLE COPY</p>							
Examiner	<i>Loke</i>		Date Considered <i>7/27/02</i>				
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